

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S24	309	257/500.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 16:11
S25	500	(257/395-397).ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 16:17
S26	1043	257/350.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 18:43
S27	1092	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same (edge or bird\$5 or beak)) and (isolation or insulat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 16:37
S28	185	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same ((edge or bird or beak) with (exten\$4 or protru\$5 or project\$3 or bump\$4))) and (isolation or insulat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 17:27
S29	597	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same (edge or bird or beak)) and (step) and @ad<"20030216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 17:48
S30	1188	257/E29.26.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 18:44